

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	502	ADVANTEST ADJ CORPORATION. as.	USPAT	OR	OFF	2004/12/10 10:04
S2	2	((("6079038") or ("6113646")).PN.	USPAT; USOCR	OR	OFF	2004/03/31 17:13
S3	5	"6079038" "6113646"	USPAT	OR	OFF	2004/03/31 14:21
S4	2	("6079038" "6113646") and shmoo	USPAT	OR	OFF	2004/03/31 17:28
S5	3	("6079038" "6113646") and (shmoo or map or graph or plot)	USPAT	OR	ON	2004/03/31 14:29
S6	403553	shmoo or map or graph or plot	USPAT	OR	ON	2004/03/31 16:09
S7	1	("6079038" "6113646") and shmoo and display	USPAT	OR	OFF	2004/03/31 14:30
S8	4516	"714"/\$.ccls. and (shmoo or map or graph or plot)	USPAT	OR	ON	2004/03/31 14:46
S9	91	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph or plot)	USPAT	OR	ON	2004/12/10 11:48
S10	27	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph or plot) and semiconductor with test\$3	USPAT	OR	ON	2004/03/31 17:09
S11	16	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or graph) and semiconductor with test\$3	USPAT	OR	ON	2004/12/10 11:53
S12	25	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph) and semiconductor with test\$3	USPAT	OR	ON	2004/03/31 14:41
S13	7	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph) and semiconductor with test\$3 and display	USPAT	OR	ON	2004/03/31 14:43
S14	7	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph) and semiconductor with test\$3 and (display or GUI)	USPAT	OR	ON	2004/03/31 14:43
S15	1	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph) and semiconductor with test\$3 and GUI	USPAT	OR	ON	2004/12/10 10:05
S16	7	("714"/\$.ccls. and (shmoo or map or graph or plot)) and (shmoo or map or graph) and semiconductor with test\$3 and GUI	USPAT	OR	ON	2004/03/31 17:30
S17	22490	"714"/\$.ccls.	USPAT	OR	ON	2004/03/31 14:46

S18	266	"714"/\$.ccls. and (shmoo or map or graph) and semiconductor with test\$3	USPAT	OR	ON	2004/04/01 12:53
S19	35	714/724.ccls. and (shmoo or map or graph) and semiconductor with test\$3	USPAT	OR	ON	2004/03/31 14:49
S20	359	"714"/\$.ccls. and GUI	USPAT	OR	ON	2004/03/31 14:50
S21	12	"714"/\$.ccls. and GUI and semiconductor with test\$3	USPAT	OR	ON	2004/04/01 15:27
S22	3	(ADVANTEST ADJ CORPORATION. as.) and GUI and semiconductor with test\$3	USPAT	OR	ON	2004/03/31 14:51
S23	3	(ADVANTEST ADJ CORPORATION. as.) and GUI	USPAT	OR	ON	2004/03/31 14:51
S24	1	("6625766").PN.	USPAT; USOCR	OR	OFF	2004/03/31 16:09
S25	403553	shmoo or map or graph or plot	USPAT	OR	ON	2004/03/31 16:09
S26	3103	shmoo or map or graph or plot	IBM_TDB	OR	ON	2004/03/31 16:09
S27	6	shmoo	IBM_TDB	OR	ON	2004/04/01 13:01
S28	9	("6061283" "6249891" "6331770" "6345373" "6360343" "6363509" "6370494" "6370675" "6557133").PN.	USPAT	OR	OFF	2004/03/31 16:18
S29	19	("4204633" "4228537" "4236246" "4527249" "4727545" "4763289" "4847795" "4862399" "4903267" "4964125" "5001714" "5010552" "5043987" "5084876" "5090014" "5161158" "5202841" "5214653" "5351247").PN.	USPAT	OR	OFF	2004/03/31 16:56
S30	47	"714"/\$.ccls. and (shmoo or map or graph) and checkerboard	USPAT	OR	ON	2004/03/31 17:02
S31	6	checkerboard with array and GUI	USPAT	OR	ON	2004/03/31 17:04
S32	4	GUI with test adj pattern	USPAT	OR	ON	2004/03/31 17:05
S33	10	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph or plot) and test adj pattern and semiconductor with test\$3	USPAT	OR	ON	2004/03/31 17:11
S34	2	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph or plot) and test adj pattern and display	USPAT	OR	ON	2004/03/31 17:12
S35	2	"6079038"	USPAT	OR	OFF	2004/03/31 17:14

S36	1	"6079038" and pattern	USPAT	OR	OFF	2004/03/31 17:14
S37	1	"6079038".URPN.	USPAT	OR	OFF	2004/03/31 17:18
S38	13	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph or plot) and DUT	USPAT	OR	ON	2004/04/01 15:25
S39	266	"714"/\$.ccls. and (shmoo or map or graph) and semiconductor with test\$3	USPAT	OR	ON	2004/03/31 17:26
S40	405	"714"/\$.ccls. and (shmoo or map or graph) and test adj pattern	USPAT	OR	ON	2004/03/31 17:26
S41	56	"714"/\$.ccls. and (shmoo or map or graph) and test adj pattern and DUT	USPAT	OR	ON	2004/03/31 17:26
S42	12	"714"/\$.ccls. and semiconductor with test\$3 and GUI	USPAT	OR	ON	2004/03/31 17:32
S43	4558	checkerboard	USPAT	OR	ON	2004/03/31 17:32
S44	4	GUI with test adj pattern	USPAT	OR	ON	2004/03/31 17:38
S45	712	714/718-742.ccls. and graph\$4	USPAT	OR	ON	2004/03/31 17:39
S46	581340	714/718-742.ccls. and graph\$4 wthe pattern	USPAT	OR	ON	2004/03/31 17:40
S47	58	714/718-742.ccls. and graph\$4 with pattern	USPAT	OR	ON	2004/03/31 17:44
S48	206	714/718-742.ccls. and graph\$4 and pattern and under adj test	USPAT	OR	ON	2004/03/31 17:44
S49	13736	714/718-742.ccls. and graph\$4 and pattern and under adj test ans shmoo adj plot	USPAT	OR	ON	2004/03/31 17:45
S50	1	714/718-742.ccls. and graph\$4 and pattern and under adj test and shmoo adj plot	USPAT	OR	ON	2004/03/31 17:47
S51	1	"20030093737"	US-PGPUB; USPAT	OR	OFF	2004/03/31 18:00
S52	1	"6079038".URPN.	USPAT	OR	OFF	2004/03/31 17:57
S53	1483	(714/724 714/723 714/721 714/745).ccls.	USPAT	OR	OFF	2004/04/01 15:21
S54	7	(714/724 714/723 714/721 714/745).ccls. and shmoo	USPAT	OR	OFF	2004/04/01 12:27
S55	314	(714/724 714/723 714/721 714/745).ccls. and test adj pattern	USPAT	OR	OFF	2004/03/31 18:05
S56	6	(714/724 714/723 714/721 714/745).ccls. and test adj pattern with map\$4	USPAT	OR	OFF	2004/03/31 18:06
S57	48	(714/724 714/723 714/721 714/745).ccls. and test adj pattern and graph\$4	USPAT	OR	OFF	2004/03/31 18:11

S58	2	(714/724 714/723 714/721 714/745).ccls. and test adj pattern with graph\$4	USPAT	OR	OFF	2004/03/31 18:09
S59	1	(714/724 714/723 714/721 714/745).ccls. and test adj pattern with plot	USPAT	OR	OFF	2004/03/31 18:09
S60	8	(714/724 714/723 714/721 714/745).ccls. and test adj pattern with display	USPAT	OR	OFF	2004/03/31 18:10
S61	4	(714/724 714/723 714/721 714/745).ccls. and test adj pattern and display near result	USPAT	OR	ON	2004/03/31 18:11
S62	1126	three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 12:28
S63	3	"714"/\$.ccls. and three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 12:30
S64	8	semiconductor and under adj test and three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 12:33
S65	200	semiconductor and three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 17:35
S66	37	test adj system and three adj dimensional adj (plot or graph)	USPAT	OR	ON	2004/04/01 12:34
S67	1378	test adj system and (three adj dimensional or 3D)	USPAT	OR	ON	2004/04/01 12:35
S68	33	test adj system with semiconductor adj device and (three adj dimensional or 3D)	USPAT	OR	ON	2004/04/01 12:36
S69	40	test\$3 with semiconductor and (three adj dimensional or 3D) adj (plot or graph or map)	USPAT	OR	ON	2004/04/01 12:41
S70	30	test\$3 with semiconductor and (three adj dimensional or 3D) adj (plot or graph or map) and pattern	USPAT	OR	ON	2004/04/01 12:42
S71	5	test\$3 with semiconductor with pattern and (three adj dimensional or 3D) adj (plot or graph or map)	USPAT	OR	ON	2004/04/01 12:43
S72	5	"714"/\$.ccls. and (shmoo or map or graph) and semiconductor with test\$3 AND checker ADJ board	USPAT	OR	ON	2004/04/01 13:05
S73	14	(shmoo or map or graph) and semiconductor with test\$3 AND checker ADJ board	USPAT	OR	ON	2004/04/01 12:55
S74	14	(shmoo or map or graph OR PLOT) and semiconductor with test\$3 AND checker ADJ board	USPAT	OR	ON	2004/04/01 12:56

S75	14	(shmoo or map or graph OR PLOT) and semiconductor with test\$3 AND checker ADJ board	USPAT	OR	ON	2004/04/01 12:56
S76	1	shmoo and semiconductor with test\$3 AND checker ADJ board	USPAT	OR	ON	2004/04/01 12:56
S77	8	three adj dimensional near (plot or graph or map)	IBM_TDB	OR	ON	2004/04/01 13:03
S78	70	three adj dimensional and (plot or graph or map)	IBM_TDB	OR	ON	2004/04/01 13:03
S79	12	three adj dimensional and (plot or graph or map) and test\$3	IBM_TDB	OR	ON	2004/04/01 13:03
S80	1	shmoo and trademark	USPAT	OR	OFF	2004/04/01 13:06
S81	223	ADVANTEST ADJ CORPORATION. as. and waveform	USPAT	OR	ON	2004/04/01 15:20
S83	13	"008408"	US-PGPUB; USPAT	OR	OFF	2004/04/01 15:22
S84	4	ADVANTEST ADJ CORPORATION. as. and waveform adj display and DUT	USPAT	OR	ON	2004/04/01 15:25
S85	359	"714"/\$.ccls. and GUI	USPAT	OR	ON	2004/04/01 15:28
S86	359	"714"/\$.ccls. and GUI	USPAT	OR	ON	2004/04/01 15:29
S87	13	714/724.ccls. and GUI	USPAT	OR	ON	2004/04/01 15:28
S88	111	"714"/\$.ccls. and GUI and pattern	USPAT	OR	ON	2004/04/01 15:31
S89	15	"714"/\$.ccls. and GUI and test adj pattern	USPAT	OR	ON	2004/04/01 15:29
S90	104	"714"/\$.ccls. and display with waveform	USPAT	OR	ON	2004/04/01 15:32
S91	47	"714"/\$.ccls. and display near waveform	USPAT	OR	ON	2004/04/01 15:32
S92	5	semiconductor near test\$3 and three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 17:33
S93	3	"714"/\$.ccls. and three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 17:48
S94	231	7\$2/\$.ccls. and three adj dimensional adj (plot or graph)	USPAT	OR	OFF	2004/04/01 17:38
S95	124	7\$2/\$.ccls. and three adj dimensional adj (plot or graph) and display	USPAT	OR	OFF	2004/04/01 17:51
S96	10	7\$2/\$.ccls. and three adj dimensional adj (plot or graph) and display and IC	USPAT	OR	OFF	2004/04/01 17:42
S97	22	7\$2/\$.ccls. and three adj dimensional adj (plot or graph)with display	USPAT	OR	OFF	2004/04/01 17:50

S98	86	7\$2/\$.ccls. and three adj dimensional adj (plot or graph) and display and test\$3	USPAT	OR	OFF	2004/04/01 17:55
S99	2	((("6079038") or ("5731984"))).PN.	USPAT; USOCR	OR	OFF	2004/04/01 17:56
S100	2	7\$2/\$.ccls. and three adj dimensional adj (plot or graph) and display and semiconductor near3 test\$4	USPAT	OR	OFF	2004/04/01 17:46
S101	2	US-6079038-\$.DID. OR US-5731984-\$.DID.	USPAT	OR	OFF	2004/12/10 11:23
S102	1	three adj dimension\$3 with (shmoo or map or graph) and semiconductor with test\$3 and GUI	USPAT	OR	ON	2004/12/10 10:06
S103	72	three adj dimension\$3 with (shmoo or map or graph) and test\$3 and GUI	USPAT	OR	ON	2004/12/10 11:41
S104	36	three adj dimension\$3 near3 (shmoo or map or graph) and test\$3 and GUI	USPAT	OR	ON	2004/12/10 10:34
S105	222	three adj dimension\$3 near3 (shmoo or map or graph) with display	USPAT	OR	ON	2004/12/10 10:07
S106	321	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3	USPAT	OR	ON	2004/12/10 10:37
S108	6	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 AND test adj pattern	USPAT	OR	ON	2004/12/10 10:11
S109	107	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 AND test	USPAT	OR	ON	2004/12/10 10:11
S110	4	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 WITH test	USPAT	OR	ON	2004/12/10 10:13
S111	11	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 SAME test	USPAT	OR	ON	2004/12/10 10:17
S112	1	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 SAME test with result	USPAT	OR	ON	2004/12/10 10:18
S113	29	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 AND test with result	USPAT	OR	ON	2004/12/10 10:20
S116	170	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 AND pattern	USPAT	OR	ON	2004/12/10 10:21

S11 7	1	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 AND pattern with test with result	USPAT	OR	ON	2004/12/10 10:22
S11 8	17	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 AND pattern with test	USPAT	OR	ON	2004/12/10 10:28
S12 2	1	"714"/\$.ccls. and three adj dimension\$3 near3 display and pattern with test	USPAT	OR	ON	2004/12/10 10:30
S12 3	11	"714"/\$.ccls. and three adj dimension\$3 near3 display	USPAT	OR	ON	2004/12/10 10:30
S12 8	17	teradyne and three adj dimension\$3	USPAT	OR	ON	2004/12/10 10:35
S12 9	6	three adj dimension\$3 near3 (shmoo or map or graph) with display\$3 and test ADJ pattern	USPAT	OR	ON	2004/12/10 10:37
S13 1	16	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or map or graph or plot) and test adj pattern	USPAT	OR	ON	2004/12/10 10:41
S13 2	12	"6079038" "5731984"	USPAT	OR	OFF	2004/12/10 11:25
S13 3	8	("6079038" "5731984") and (x y z)	USPAT	OR	OFF	2004/12/10 11:27
S13 7	96303	"x" with "y" with "z"	USPAT	OR	OFF	2004/12/10 11:28
S13 8	1267	"x" with "y" with "z" and test with pattern	USPAT	OR	OFF	2004/12/10 11:29
S13 9	21	"x" with "y" with "z" with display and test with pattern	USPAT	OR	OFF	2004/12/10 11:55
S14 1	88	"714"/\$.ccls. and "x" with "y" with "z" and test with pattern	USPAT	OR	OFF	2004/12/10 11:33
S14 2	9	"714"/\$.ccls. and "x" with "y" with "z" with test with pattern	USPAT	OR	OFF	2004/12/10 11:34
S14 5	21	"x" with "y" with "z" with display and test with pattern	USPAT	OR	OFF	2004/12/10 11:39
S14 6	8	"x" with "y" with "z" with plot and test with pattern	USPAT	OR	OFF	2004/12/10 11:41
S14 7	424	"x" with "y" with "z" with (shmoo or map or graph) and test\$3	USPAT	OR	ON	2004/12/10 11:41
S14 8	52	"x" with "y" with "z" with (shmoo or map or graph) same test\$3	USPAT	OR	ON	2004/12/10 11:42
S14 9	36	"x" with "y" with "z" with (shmoo or map or graph) and test with pattern	USPAT	OR	ON	2004/12/10 11:44

S15 0	17	"x" with "y" with "z" with (shmoo or map or graph) and test with pattern and integrated with circuit	USPAT	OR	ON	2004/12/10 11:44
S15 1	11	(ADVANTEST ADJ CORPORATION. as.) and (shmoo or graph) and semiconductor with test\$3 with pattern	USPAT	OR	ON	2004/12/10 11:53
S15 2	1	"x" with "y" with "z" with display same test with pattern	USPAT	OR	OFF	2004/12/10 11:56
S15 3	21	"x" with "y" with "z" with display and test with pattern	USPAT	OR	OFF	2004/12/10 11:56